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				Application Number	10/646,013		
INF	ORMATION D	ISCLC	SURE	Filing Date	8/22/2003		
STA	TEMENT BY	APPL	ICANT	First Named Inventor	Cheng H. Huang		
				Art Unit	2826		
	(Use as many sheets a	as necassar)	1)	Examiner Name	Remmon R. Forde		
Sheet	1	of	1	Attorney Docket Number	A1063		

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1.7.		V. KLEE et al. "A 0.13 um logic-based embedded DRAM technology with electrical fuses, Cu interconnect in SiLK, sub-7ns random access time and its extension to the 0.10 um generation," IEEE (c) 2001 IEDM (International Electron Devices Meeting), Technical Digest, pp 18.5.1-18.5.4	
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							Application Number	10/646,013	
	INFO	RMATION	V DIS	CL	os	URE	Filing Date	8/22/03	
STATEMENT BY APPLICANT				-IC	ANT	First Named Inventor	Cheng H. Huang et al.		
							Art Unit	2811	-
	(Use as many sheets as necessary)				ry)		Examiner Name	Remmon R. Forde	
	Sheet	1	i	of		1	Attorney Docket Number	A1063	

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1		WEI ZHANG et al., "Reliability of laser-induced metallic vertical links,"									
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1 2		JB BERNSTEIN et al. "Laser energy limitation for buried metal cuts" IEEE Electron Device Letters, pp 4-6, Jan. 1998, Vol. 19, Issue 1									
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1. %		RT SMITH et al. "Laser programmable redundancy and yield improvement in a 64 K DRAM", IEEE Journal of Solid-State Circuits, pp 506-514 October 1981, Vol. 16, Issue 5									
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